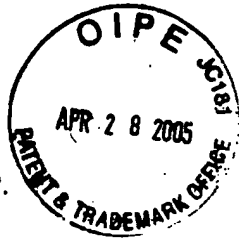


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CUSTOMER NO. 32,986
IP STRATEGY GROUP, P.C.
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San Jose, CA 95170-0640

PATENT APPLICATION
ATTORNEY DOCKET NO. LMRX-P036/P1213

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: KIM et al.
Application No.: 10/813,913
Filed: 3/30/2004

Examiner: PERT, Evan T.
Group No.: 2826
Confirmation No.: 5070

Title: METHODS AND APPARATUS FOR
INSPECTING CONTACT OPENINGS IN A PLASMA
PROCESSING SYSTEM

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the
US Postal Service as First Class Mail in a postage-paid envelope
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Alexandria, VA 22313-1450 on April 26, 2005.
Signed: /Alma Fazlic/
Alma Fazlic

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

The references listed in the attached PTO Form 1449 may be material to the patentability of the above-identified patent application. Applicants submit the list of these references in compliance with their duty of disclosure pursuant to 37 CFR §§ 1.56 and 1.97. The Examiner is requested to make these references of official record in this application.

This Information Disclosure Statement is not to be construed as a representation that a search has been made, that additional information material to the examination of this application does not exist, or that these references indeed constitute prior art.

This Information Disclosure Statement is believed to be filed before the mailing date of a first Office Action on the merits. If it is determined that fees are due, the Commissioner is hereby authorized to charge such fees to Deposit Account 50-2284 (Order No. LMRX-P036).

Respectfully submitted,

By: /Joseph Nguyen/
Joseph Nguyen
Reg. No. 37,899



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US PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number	Publication Date	Name of Patentee or Applicant	Reference to Related Case
	1	US 5,288,367	1994-02-22	Angell et al.	

OTHER DOCUMENTS

Examiner Initials	Cite No.	Description	T
	2	ROBBINS et al., "An Investigation of the Plasma Chemistry Involved in the Synthesis of ZnO by PECVD," Journal of the Electrochemical Society, 150 (10), pp. C693-C698, 2003	
	3	WU et al., "Towards a Complete Plasma Diagnostic System," 4 pages total	
	4	SHUL et al., "Group-III Nitride Etch Selectivity in BCl ₃ /Cl ₂ ICP Plasmas," 11 pages total, MRS Internet J. Nitride Semicond. Res. 4S1, G8.1 (1999)	

Examiner Signature		Date Considered	
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